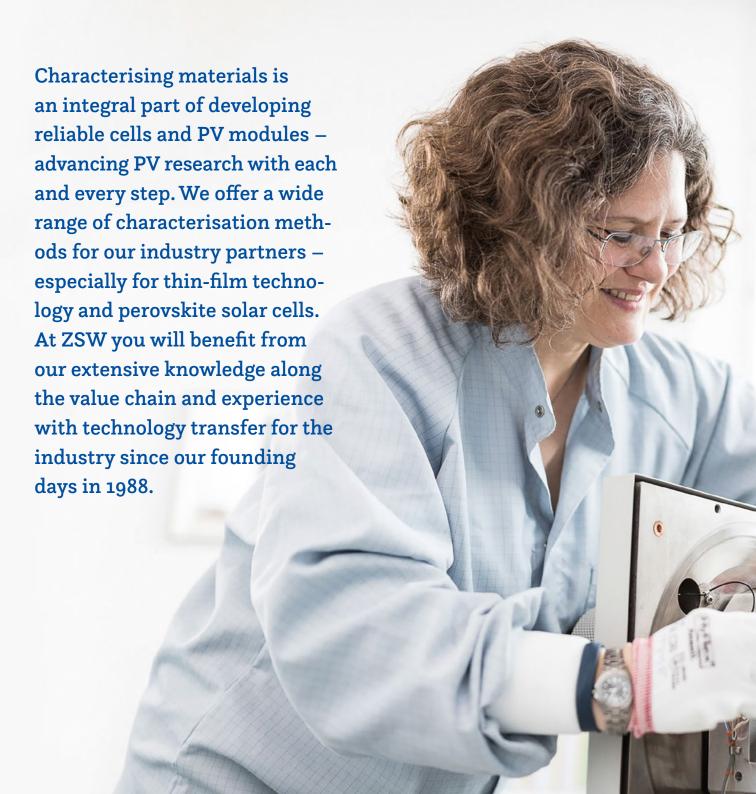


**ZSW PHOTOVOLTAICS** 

## MATERIALS RESEARCH

Thin-film characterisation services







Materials Characterisation	Tool	Purpose
EDX Energy-Dispersive X-ray Spectroscopy	Oxford Instruments Be(4) - U(92)	High-spatial-resolution composition by electron-beam-excited x-ray analysis
<b>FIB-SEM</b> Focussed Ion Beam-Scanning Electron Microscope	Zeiss Crossbeam 550 1 nm resolution, 10 nm film thickness	High-resolution imaging and milling
GDOES Glow Discharge Optical Emission Spectroscopy	Horiba GD Profiler 2 Element list available upon request	Depth profiles of composition by optical emission in plasma
Raman Spectroscopy	<b>S&amp;I</b> (325, 442, 459, 488 nm) <b>WiTec Microscope</b> (532, 785 nm)	Phase identification by bond oscillations
<b>ToF-SIMS</b> Time-of-Flight Secondary Ion Mass Spectrometry	IonTof TOF.SIMS 5 Analysis Bi <sup>+</sup> , Sputter Cs <sup>+</sup> , O <sub>2</sub> <sup>-</sup> , Ar cluster, O cluster; 200 nm lateral resolution, 6000 mass resolution, 1-2000 amu	Composition by mass spectrometry, depth profiles and 3D composition imaging
XPS X-ray Photoelectron Spectroscopy	<b>SPECS</b> Mg 1254 eV, Al 1487 eV and Cr 5417 eV	Surface elements and their chemical state
XRD X-ray Diffraction	Panalytical – Empyrean Cu-Kα, Bragg-Brentano or grazing incidence geometries	Phase identification by crystal structure
XRF X-ray Fluorescence	Fischerscope X-ray XVD-SDD Al(13) - U(92)	Composition and thickness of thin films
Optical/Optoelectrical Method	Tool	Purpose
OBIC, PL Mapping Optical Beam Induced Current, Photoluminescence	Home-built tool	Homogeneity of current generation, material quality
Optical microscope	Zeiss Axio	Identification of features, inspection of grid fingers and scribes
Optical spectroscopy UV-Vis-NIR with integrating sphere	PerkinElmer Lambda 900 Avantes AvaSpec	Optical characteristics: transmission, reflection, scattering
Profilometry	Keyence/Bruker DektakXT	Optical/tacticle profilometry
Quantum Efficiency	Bentham	Spectral distribution of current generation and collection
Spectral Ellipsometry	Sentech/Woolam	Optical constants and film thickness for very thin flat films
TRPL Time-Resolved Photoluminescence	PicoQuant FluoTime 300 450 nm and 640 nm lasers	Calculation of charge carrier lifetimes from photoluminescence decay



Electrical Characterisation Method	Tool	Purpose
CV Capacitance-Voltage	Home-built tool	Calculation of charge carrier concentration
<b>DLIT</b> Dark Lock-In Thermography	Home-built tool with Thermo-sensorik IR camera	Imaging method to localize short circuits and current leakage
<b>DLTS</b> Deep-Level Transient Spectroscopy	PhysTech	Defect characterization
EL Electroluminescence	Andor i-Kon in darkbox	Imaging method for localisation of regions and faulty contacts
Hall effect	PhysTech RH 2010	Calculation of charge carrier concentration and mobility
Low-Temperature Characterization	ARS cryogenic probestation	Temperature dependency and low- temperature characterization of e. g. IV, CV
Transient Current-Voltage-Capacitance	Fluxim Paios	In-depth electrical characterization of perovskite solar cells
Solar Simulators, IV Current-Voltage characterization	<b>Wacom</b> (1- or 2-lamp, up to 10 × 10 cm²) <b>ABET</b> (up to 30 × 30 cm²)	Calculation of solar parameters for cells or modules in substrate or superstrate configurations, temperature adjustable
Sheet resistance Four Point Probe Mapping	Home-built tool up to 30 × 30 cm <sup>2</sup>	Calculation of sheet resistance

## Contact us

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